



## ELECTRICAL CHARACTERISTICS (T<sub>case</sub> = 25°C unless otherwise stated)

Parameter	Test Conditions	Min.	Typ.	Max.	Unit
BV <sub>DSS</sub> Drain-Source Breakdown Voltage	V <sub>GS</sub> = 0 I <sub>D</sub> = 10mA	65			V
I <sub>DSS</sub> Zero Gate Voltage Drain Current	V <sub>DS</sub> = 28V V <sub>GS</sub> = 0			1	mA
I <sub>GSS</sub> Gate Leakage Current	V <sub>GS</sub> = 20V V <sub>DS</sub> = 0			1	µA
V <sub>GS(th)</sub> Gate Threshold Voltage*	I <sub>D</sub> = 10mA V <sub>DS</sub> = V <sub>GS</sub>	1		7	V
g <sub>fs</sub> Forward Transconductance*	V <sub>DS</sub> = 10V I <sub>D</sub> = 0.2A	0.18			mhos
G <sub>PS</sub> Common Source Power Gain	P <sub>O</sub> = 750mW	11			dB
η Drain Efficiency	V <sub>DS</sub> = 12V I <sub>DQ</sub> = 75mA	40			%
VSWR Load Mismatch Tolerance	f = 1GHz	10:1			—
C <sub>iss</sub> Input Capacitance	V <sub>DS</sub> = 0V V <sub>GS</sub> = -5V f = 1MHz			12	pF
C <sub>oss</sub> Output Capacitance	V <sub>DS</sub> = 28V V <sub>GS</sub> = 0 f = 1MHz			6	
C <sub>rss</sub> Reverse Transfer Capacitance	V <sub>DS</sub> = 28V V <sub>GS</sub> = 0 f = 1MHz			0.5	

\* Pulse Test: Pulse Duration = 300 µs , Duty Cycle ≤ 2%

## THERMAL DATA

R <sub>THj-case</sub>	Thermal Resistance Junction – Case	Max. 70°C / W
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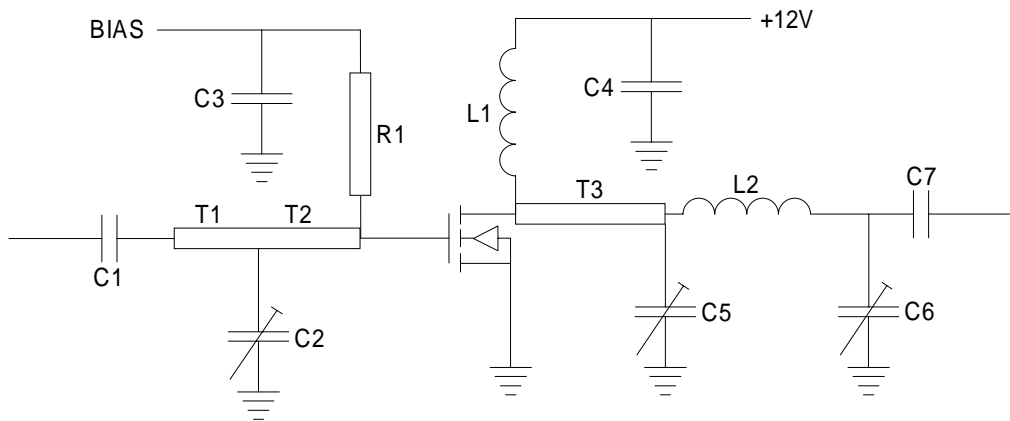
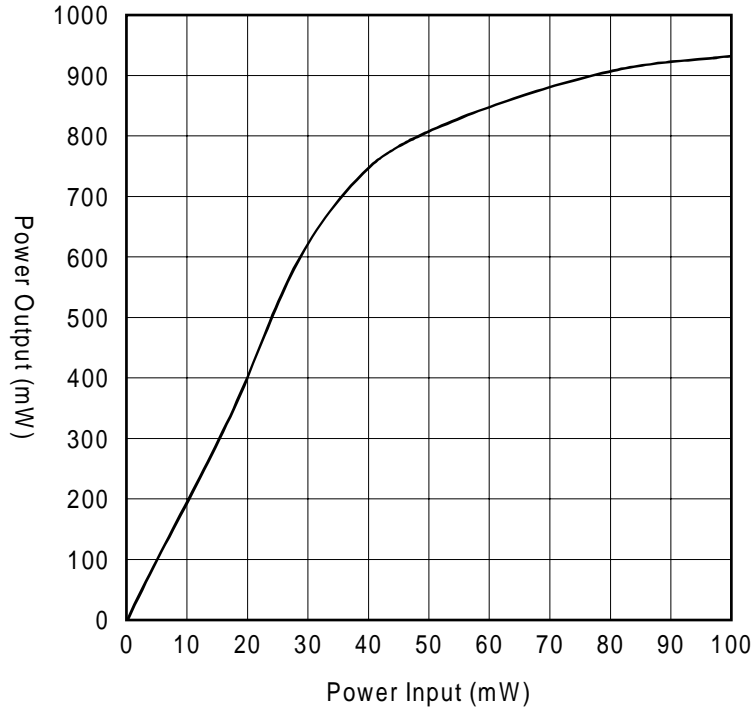
### S Parameters at V<sub>d</sub> = 12V, I<sub>d</sub> = 75mA

Freq MHz	S11		S12		S21		S22	
	mag	ang	mag	ang	mag	ang	mag	ang
300	0.47	-95	0.04	50	5.20	90	0.32	-90
400	0.46	-120	0.05	80	4.40	76	0.35	-91
500	0.47	-131	0.07	100	3.50	68	0.38	-94
600	0.49	-146	0.10	110	3.00	59	0.43	-98
700	0.51	-156	0.15	110	2.60	51	0.48	-103
800	0.53	-163	0.20	104	2.30	45	0.54	-108
900	0.54	-180	0.25	100	2.10	40	0.58	-112
1000	0.55	178	0.29	96	1.80	36	0.60	-116
1100	0.56	175	0.34	91	1.60	33	0.63	-120
1200	0.57	163	0.40	85	1.40	28	0.65	-126
1300	0.58	150	0.45	80	1.30	26	0.66	-129
1400	0.60	144	0.48	75	1.20	24	0.66	-133
1500	0.60	140	0.52	70	1.10	22	0.66	-135
1600	0.59	130	0.55	66	1.00	21	0.65	-138
1700	0.58	123	0.58	63	0.95	20	0.65	-140
1800	0.56	115	0.60	58	0.90	19	0.64	-142
1900	0.54	110	0.62	54	0.90	20	0.64	-144
2000	0.51	108	0.62	50	0.90	20	0.63	-145

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## TYPICAL PERFORMANCE D2081UK at 1GHz

Bias Conditions  $V_d = 12V$ ,  $I_{dq} = 75mA$



D2081UK 1GHz Test Circuit

C1, C7 33pF ATC100B

C2, C5, C6 1–8pF

C3, C4 1000pF NPO

L1 0.1 $\mu$ H

L2 10mm of 1.6mm tcw (half turn)

T1 50 $\Omega$  microstrip, 11mm long

T2 50 $\Omega$  microstrip, 15mm long

T3 50 $\Omega$  microstrip, 5mm long

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